

circuit includes a first logic circuit for recognizing the presence of a potential flaw if the energy level of the reflected shear waves sensed by said shear wave sensing circuit is less than a predetermined level.

Please amend claim 6 as follows:

6. (Once amended) The defect detection system of claim 5 in which said detection circuit includes a surface Rayleigh wave sensing circuit for sensing the energy level of the surface Rayleigh waves at the time of arrival of the surface Rayleigh wave at the detection laser system.

Please amend claim 7 as follows:

7. (Once amended) The defect detection system of claim 6 in which said detection circuit includes a second logic circuit for inhibiting recognition of a potential flaw if the energy level of the surface Rayleigh waves sensed by said surface Rayleigh wave sensing circuit is less than a predetermined level and confirming recognition if it is greater than the predetermined level.

Marked up copies of claims 4-7, indicating the above amendments, are attached hereto.

REMARKS

The applicant appreciates the Examiner's thorough examination of the application and requests reexamination and reconsideration of the application in view of the preceding amendments and the following remarks. The amendments presented above contain no new matter and raise no new issues.